

Training Course Data Sheet	
<h1>Aspen DMCplus[®]</h1> <h2>Advanced Concepts</h2>	Course Number: MA305
	Duration: 5 days
	CEUs Awarded: 3.5
	Level: Advanced

Objective

- To learn about the benefits and potential pitfalls in using prediction error feedforward techniques to improve model accuracy
- To learn about the details of controlling ramp (integrating) variables
- To understand the techniques required to obtain model consistency and close material balances in the Aspen DMCplus steady state optimization
- To understand the techniques involved in characterizing non-linear transformations.
- To learn the details of designing and implementing an Aspen DMCplus Composite suite
- To learn the fundamentals of parametric identification using subspace identification technology

Course Benefits

- Develop skills required to design, implement, and troubleshoot complex Aspen DMCplus controllers to generate increased APC benefits at your facility

Who Should Attend

- Engineers who are designing or implementing Aspen DMCplus controllers
- Engineers who are responsible for maintaining Aspen DMCplus controllers

Approach

- Descriptions of advanced design concepts
- Demonstrations of the offline and online tools that illustrate the advanced concepts
- Hands-on exercises that illustrate the advanced concepts complement the theory sessions
- Course notes are provided
- Review quizzes reinforce each day's learning

Prerequisites

- Attend Course "Introduction to Multivariable Predictive Control with Aspen DMCplus"
- Field experience with commissioning at least one project with the Aspen DMCplus controller and a familiarity with chemical process engineering and/or process operations
- Familiarity with the process control computer and distributed control system
- Some familiarity with using Microsoft operating systems. The course is presented in a Windows 2000 Professional environment

Aspen DMCplus Advanced Concepts Course Agenda

Day 1

- Review of basic Aspen DMCplus technology
 - Overview of advanced controller issues and tasks
 - Advanced Identification Techniques
 - Identification with valve saturation
 - Understanding partial independence
 - Using prediction error feedforward
 - Dealing with noisy regulatory controllers
 - Ramp Variable Techniques
 - Advantages and drawbacks of breaking PI level loops
 - Ramp implications for prediction error updating – using the ramp rotation factor
 - Ramp handling in the steady state optimization – balancing the ramp
 - Ramp imbalance calculations – using the ramp horizon and safety zones
 - Ramp handling in the dynamic move calculation – using the ramp rate and ramp setpoint
 - Using pseudo-ramps
 - Lab exercise: Modeling using the prediction error feedforward technique
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Day 2

- Lab exercise: Controlling a Ramp
 - Steady State Optimization Advanced Techniques
 - Closing the mass balance
 - Pivoting technique to deal with ramps in the middle of a plant; how to compute the LP costs
 - Using Singular Value Decomposition (SVD) and Relative Gain Analysis (RGA) to avoid numerical instability
 - Gain matrix analysis in Aspen DMCplus Model
 - Dealing with parallel processes
 - Comparison of LP vs. QP
 - Lab exercise: Using the ramp pivoting technique to calculate LP costs
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Day 3

- Special Dynamic Topics
 - Move suppression
 - Equal concern errors
 - Move compression and resolution issues
 - Prediction error filtering
 - Variable Transformations
 - Why transforms are needed
 - Standard transform types and examples
 - Detailed list of transformed parameters
 - Using input/output calculations
 - Gain scheduling
 - Lab exercise: Identifying and modeling valve output transforms and using Gain Matrix Analysis
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Day 4

- Subcontrollers and External Targets
 - Subcontrollers: basic definition, guidelines for use, implementation guidelines, configuration parameters
 - External Targets: basic definition, implementation guidelines, configuration parameters, validation
 - Aspen DMCplus Composite
 - Justification for using Composite
 - Composite tiers
 - Composite calculation steps
 - Composite participation modes and states
 - Timeout flags
 - Aliasing
 - Composite initialization file
 - Composite parameters in the CCF
 - Using and configuring the CCF Switcher
 - Lab exercise: Using Aspen DMCplus Composite and the CCF Switcher
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Day 5

- Introduction to Subspace Identification
 - Overview of MPC modeling technologies: FIR, ARX, state space models
 - State space model example and characteristics
 - Subspace identification technology
 - Subspace identification parameters
 - Subspace identification guidelines
 - Using multiple data sets in Aspen DMCplus Model

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